



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

#4/a
5/1/2
Sunder

In re Application of:

Rodolfo I. Gamboa

Docket No.: TI-29518

Serial No.: 09/735,668

Examiner: Farahani, D.

Filed: 12/20/00

Art Unit: 2814

For: SEMICONDUCTOR TEST SOCKET HAVING POGO-PIN CONTACTS

Amendment under 37 CFR 1.115

Assistant Commissioner of Patents
Washington, DC 20231

MAILING CERTIFICATE UNDER 37 C.F.R. §1.8(A)

I hereby certify that this correspondence is being deposited with the
U.S. Postal Service as First Class Mail in an envelope addressed to:
Assistant Commissioner for Patents, Washington, D.C. 20231 on

4-16-02

Marianna Smith
Marianna Smith

Dear Sir:

The following amendments and remarks are offered in response to the
Examiner's Office Action dated 01/16/02. They are respectfully submitted as a
full and complete response to that Action.

Please amend the above-referenced application as follows:

In the Claims:

Please amend the claims as follows:

1. (amended) A test socket for a semiconductor device having a plurality of
pins, the test socket comprising:
a body for receiving a semiconductor device, the body having an integrally
formed guidepost and a chamfered impact base;

RECEIVED
APR 25 2002
TECHNOLOGY CENTER 2800